



Silicon Detectors and Current Developments

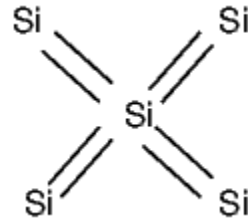
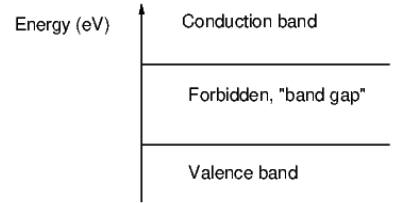
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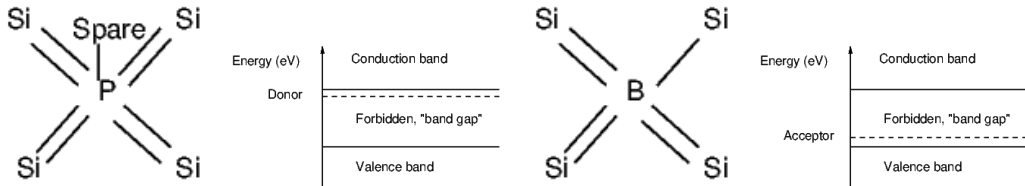
Introduction: Me and ATLAS
Brief reminder of the basics
Improvements for ATLAS
Current Developments
Conclusions

- ▶ Employed here at TRIUMF
- ▶ Detector Development in the Science Technology department (since Aug 2016)
- ▶ ATLAS experiment (Since 1994)
- ▶ Worked on assembling about 1000 detectors into an endcap for ATLAS (delivered 2007)
- ▶ Then went onto prepare the next inner tracker as upgrade coordinator (to run in 2026)
- ▶ Currently working on designing end-cap sensors; ramping up to building them

- ▶ See for example Knoll's textbook on particle detectors
- ▶ Semiconductors
- ▶ Doping
- ▶ np junction
- ▶ Biasing and depletion
- ▶ Passage of Charged Particles

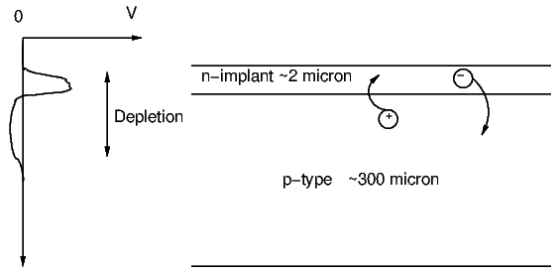
- ▶ Electrons in crystalline solids have a forbidden energy gap: the “band gap”
- ▶ Below this, electrons are either confined to their atom or confined to the covalent bonds between atoms (valence electrons).
- ▶ Above it they are free to move around.
- ▶ In insulators, the band gap is 5 eV or greater. At room temperature, all valence electrons are in the valence band, none available to conduct: very high resistivity ($10^{16} \Omega\text{cm}$)
- ▶ In semiconductors, the band gap is around 1 eV: at room temperature, some valence electrons get thermal kick into the conduction band. Intermediate resistivity ($10^5 \Omega\text{cm Si}$)
- ▶ In metals, there is no significant band gap and most valence electrons are free: very low resistivity
- ▶ In semiconductors, when an electron gets promoted to the conduction band, a positive charged Si is left behind. However, electrons can hop from neighbouring bonds into the missed bond. The hole can move, and contributes to conduction.



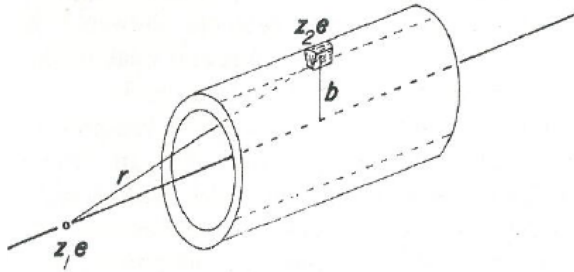


- ▶ Insertion of Group-V atom such as phosphorous in place of a Si atom:
 - ▶ Has one electron left over, at an energy level just below the conduction band
 - ▶ Can easily "give" an electron to the conduction band, hence called a donor
 - ▶ Thermal excitation promotes almost all such electrons to the conducting band, leaving a *fixed* positive charge site. Not a hole - it cannot move.
 - ▶ Conduction predominantly by electrons: n-type
- ▶ Insertion of a group-III atom such as Boron
 - ▶ Has a missing electron: can accept electrons, hence called acceptor
 - ▶ Energy level is just above valence band
 - ▶ Almost all such gaps get filled, leaving a hole behind. The hole is free to move.
 - ▶ Conduction predominantly by holes, called p-type

- ▶ Suppose we take a p-doped wafer, and implant a high density of donor atoms making an n-layer (called n^+)
- ▶ Conduction electrons diffuse from the high-density n^+ region to the low electron density p region
- ▶ Holes diffuse from the hole-rich p region to the n^+ region
- ▶ Builds up an E-field which opposes further diffusion: Dynamic equilibrium reached.
- ▶ There is a region with very few charge carriers: the depletion region
- ▶ Very low conductivity



- ▶ Apply $V > 0$ to the n^+ side, and connect ground to p-side
- ▶ Called reverse bias, because it tries to move e^- from p to n, holes from n to p, but there are very few of these
- ▶ Extra field increases the depletion region, with very little current (only minority carriers can flow)
- ▶ (A forward bias on the other hand generates a big current, principle of diodes)
- ▶ At sufficiently high bias, the depletion region extends through the whole p region - “fully depleted”



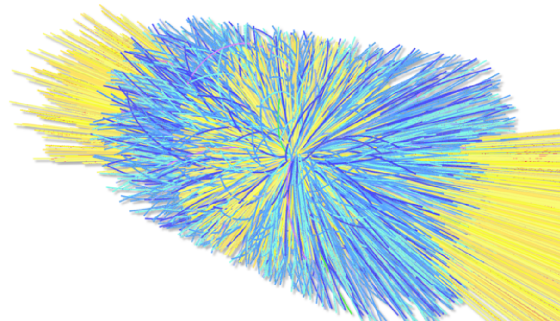
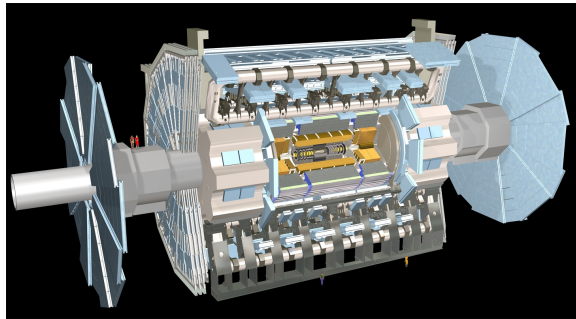
- ▶ Saw in Mike Vetterli's talk what a charged particle does in a gas: kicks electrons sideways
- ▶ In semiconductors, most interactions give too small a kick to promote a valence electron to the conduction band
- ▶ Instead, the whole atom moves and generates phonons in the lattice: very low energy
- ▶ A small fraction of the time, sufficient energy is given to an electron to promote it from valence to conduction band, leaving a hole
- ▶ The reverse bias voltage rapidly sweeps these away, giving a current; this current can be amplified and detected in electronics connected to the implant: you have a particle detector!
- ▶ In Si, band gap $E_g \approx 1.115$ eV; mean energy deposited per e-hole pair $\epsilon \approx 3.62$ eV. Difference is dispersed in phonons, heat etc.

- ▶ Efficiency
 - ▶ Maximise signal collection, minimise noise, allows low threshold
 - ▶ Minimise gaps and other dead areas
- ▶ Energy Resolution
 - ▶ Low energy: particle stops, depositing all its energy. Charge collected proportional to particle energy
 - ▶ Statistical fluctuations dominated by number of interactions, not electrons: small “Fano factor”, very good resolution

Medium energy: measure dE/dx . Combine with momentum measurement to identify e , π , K and heavier
- ▶ Timing
 - ▶ More later. 50 ps timing available; 10 ps on the horizon.
 - ▶ Gives particle velocity (low energy) or position (high energy, $v = c$)
- ▶ Position Resolution
 - ▶ Smaller pixels and narrower strips give better position resolution
 - ▶ High signal to noise with analogue readout: use centre-of-gravity of strip/pixel clusters. Can achieve $1 \mu\text{m}$ resolution.
- ▶ Radiation Length
 - ▶ For inner trackers, material is bad: photon conversions, electron bremsstrahlung, nuclear interactions, multiple scattering
 - ▶ Thinner detectors, and low-z stiff materials for supports, low power and special cooling systems desirable

- ▶ ATLAS as illustration of scale and what is needed
- ▶ Other fields exist
- ▶ Goals of improvements
- ▶ Select a few topics for more depth

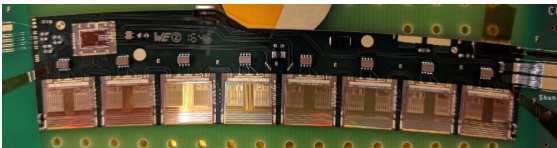
- ▶ LHC will upgrade to HL-LHC with almost 10 times the luminosity
- ▶ Will need a new inner tracker
 - ▶ Radiation damage: current detector would die at currently expected LHC rates in about 2024
 - ▶ The density of hits (occupancy) would be around 5 %, hard to disentangle tracks
 - ▶ New front-end intelligence needed for fast triggers
- ▶ Scale:
 - ▶ 7 m long x 2 m diam; 5000 M pixels, 60 M strips
 - ▶ 14 m² pixel detectors, 125 m² strip detectors
 - ▶ 120 MCHF (40 MCHF Pixels, 60 MCHF strips, 20 MCHF common items)



- ▶ Nuclear Physics
- ▶ Medical: continuous imaging during operations
- ▶ X-ray quality control: weld inspection (huge doses)
- ▶ Space telescopes
- ▶ X-ray imaging at synchrotron light sources
 - ▶ Pharmaceuticals
 - ▶ Biophysics
 - ▶ Molecular biology
- ▶ Many others apart from my field of particle detectors

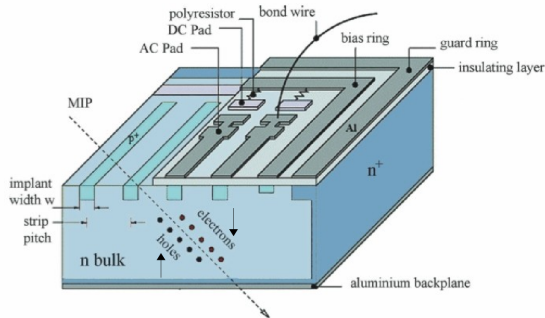
- ▶ Although semi-conductor devices have been around many decades and do a fantastic job, they still have a lot of room for improvement
 - ▶ Position resolution: smaller diode sizes
 - ▶ Timing resolution: avalanche diodes for 10 ps timing; 50 ps timing in normal pixel detectors
 - ▶ Radiation hardness: particle physics, industrial use, medical use
 - ▶ Less dead area between sensors: medical imaging
 - ▶ Lower power for easier cooling, less dead material (or fancy cooling systems)
 - ▶ Data rates: LHC upgrade will have much higher data rates; major developments in readout chips
 - ▶ High speed links (> 10 GHz)
 - ▶ Internal bus and storage architecture: per-pixel storage, read only triggered events
 - ▶ “Front-end intelligence”: data reduction at the sensor
 - ▶ Partial readout for fast trigger
 - ▶ Cost: with large detectors like ATLAS and LHC, cost per detector limits what we can do
- ▶ I will go through several development lines all looking to improve one or more of these

- ▶ ATLAS Strips
- ▶ 3D sensors
- ▶ Edgeless sensors and small guard ring structures
- ▶ SiPM
- ▶ Monolithic active pixel sensors (MAPS)/CMOS sensors



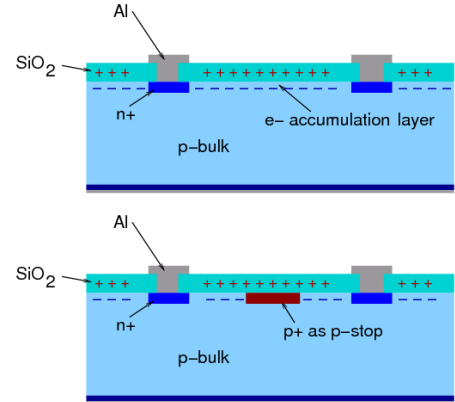
- ▶ Shorter strips (technically difficult to make narrower): lower occupancy
 - ▶ 12 cm \rightarrow 2.5 cm
- ▶ Higher signal-to-noise:
 - ▶ Use n-in-p, collect e^- : faster drift, less loss of e^- in radiation damage sites
 - ▶ Shorter strips mean less capacitance on amplifier, so lower noise
 - ▶ Design to allow high bias voltage and E-fields: fast collection, less trap losses
- ▶ Also: n-in-p avoids type inversion...



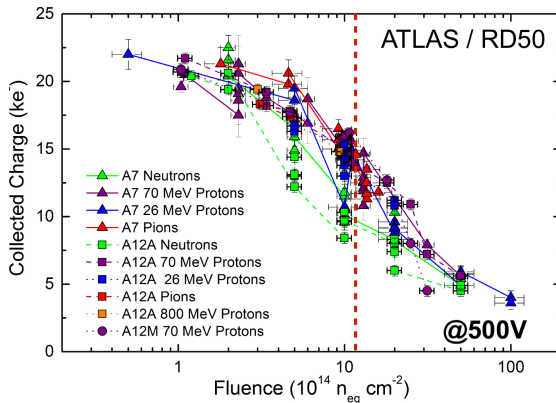


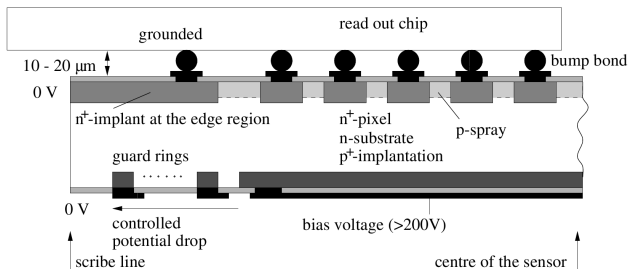
- ▶ Current ATLAS strip-detector uses p strips in n doped substrate
 - ▶ Cheap to produce, works well with the doses expected before HL-LHC
 - ▶ Radiation damage: substrate eventually turns to p-type
 - ▶ Junction moves to the back plane with n+ implant
 - ▶ Depletion zone grows from there to the p-strips: requires full depletion (high HV)
 - ▶ Otherwise signal drops off rapidly as the non-depleted region grows
 - ▶ Insufficiently rad-hard for HL-LHC.
- ▶ Solutions:
 - ▶ n+ in n: expensive, double side processing
 - ▶ n in p: chosen for ITk

- ▶ Need for p-stop or p-spray isolation between segmented n^+ strips:
 - ▶ The SiO_2 layer builds up +ve charge
 - ▶ This attracts a layer of e^- just below it
 - ▶ This dipole gives high capacitance between strips
 - ▶ High noise and signal sharing between strips
 - ▶ Surrounding each strip by a p^+ implant interrupts these electrons giving good interstrip isolation
 - ▶ Many p-stop layouts prototyped for optimisation of ATLAS sensors



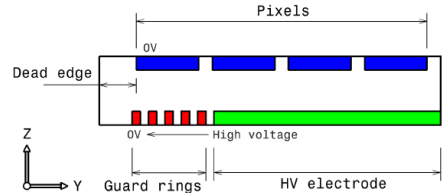
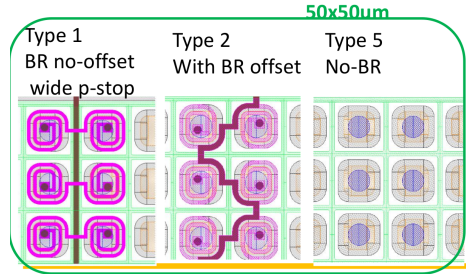
- ▶ How do we know our sensors will work after 10 years at HL-LHC?
- ▶ Large program at many radiation sources, Neutron, pion, proton, X-ray, ...
- ▶ Many sensors, both full-size and miniature
- ▶ Irradiate at high rate (10 years condensed into a few hours)
- ▶ measure: iv curves, noise, and signal in test beam
- ▶ Performance after irradiation remains good
 - ▶ $S/N > 10$
- ▶ Leakage current low provided the detectors are run cold ($-20\text{ }^{\circ}\text{C}$)
 - ▶ CO_2 evaporative cooling





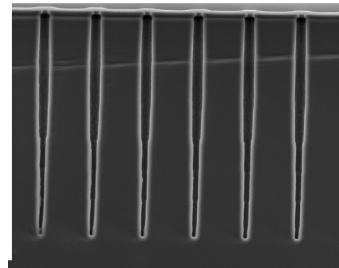
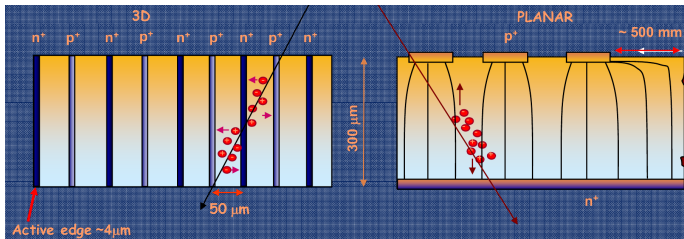
- ▶ Pixel advantages over strips:
 - ▶ 2D info in a single detector: no ghosts, similar material cf. two strip layers
 - ▶ Small diode size: high position resolution, low capacitance and noise so very rad hard
 - ▶ Low occupancy, less confusion in tracking
- ▶ As used in current ATLAS and continues as part of base-line for future ATLAS upgrades

- ▶ Small is beautiful: better resolution, lower occupancy, separate tracks in high density jets
- ▶ Current ATLAS pixels $50\ \mu\text{m} \times 400\ \mu\text{m}$. Limited by readout electronics.
- ▶ Going from 250 nm to 65 nm readout-chip technology allows smaller pixels
- ▶ Develop 50×50 and $25 \times 100\ \mu\text{m}^2$ pixel sensors
 - ▶ Effects at pixel edges more critical
 - ▶ Field effects of bias rail etc. need care
 - ▶ Bump bonding more critical \$\$\$
- ▶ Also develop designs with narrow guard rings to reduce dead area between sensors
 - ▶ Allow pixels over the guard structures

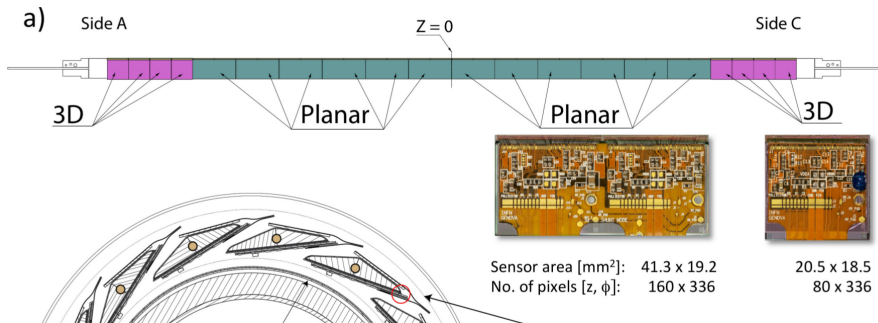


<https://cds.cern.ch/record/1233750> Lounis et al.

- ▶ Leakage current
 - ▶ Pixels are nearest the interaction point, and receive about ten times the dose of the strips
 - ▶ Leads to high leakage current and large high voltage to achieve full depletion
 - ▶ This current is a source of heat
 - ▶ Cooling becomes very critical: high temperatures give high leakage current gives even higher temperatures:
 - ▶ “Thermal Runaway”
 - ▶ Micro-channel CO₂ cooling? Or, reduce the cause of the problem with 3D pixels
- ▶ Cost:
 - ▶ Separate sensor and readout chip \$\$
 - ▶ Bump bonding especially for small pixels \$\$\$
 - ▶ ...Investigate MAPS, CMOS, DMAPS...



- ▶ In planar sensors, charge drifts the entire thickness of the sensor
- ▶ Initial drift signal spreads over several pixels, and after radiation damage gets lost in traps
- ▶ Can thin the planar sensor for lower voltage, but you are losing signal
- ▶ 3D sensors keep full signal while reducing trapping and heat production (same current, lower HV)
- ▶ Made possible with Deep Reactive Ion Etching (DRIE)
 - ▶ Process used in 3D memory chips: circuitry is on one side of a wafer. Thin the wafer, stack several layers. But how to connect layers electrically? DRIE drills deep holes which can be filled with metal for conduction.
- ▶ Edgeless: highly efficient right up to the edge.



- ▶ Used in ATLAS IBL, new (2015) innermost pixel layer
- ▶ And in very forward ATLAS detectors (AFP)
- ▶ Helps solve over-heating problem at HL-LHC

- ▶ Monolithic Active Pixel devices: charge liberated in a CMOS chip is amplified in that same chip
- ▶ Used at ALICE and other experiments
- ▶ Only partially depleted region; relies on diffusion for charge to travel to depleted region
- ▶ Problems:
 - ▶ Fill factor: if a large part of the chip is covered in logic circuitry, regions below are insensitive
 - ▶ Slow: not good for timing
 - ▶ Not rad-hard: plenty of time for charges to fall into traps
 - ▶ High speed logic circuitry to process high data rates tends to generate noise

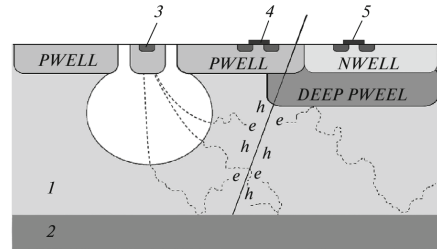


Fig. 1. Scheme for collecting the charge formed by an ionizing particle in a MAPS pixel cell with a deep p -well [1]: (1) epitaxial layer P^- ; (2) substrate P^{++} ; (3) signal diode; (4) NMOS transistor with a p -well; (5) PMOS transistor with an n -well.

V.I. Zhrebchevsky et al. Bulletin of the Russian academy of sciences, 2016, Vol. 80, No. 8

(CMOS: technology mixing n and p transistors, allowing for “complementary” logic which only uses power during switching states, not in-between states)

- ▶ Industry standard reliable production, huge volume rate available
- ▶ Low wafer cost compared to specialised sensor silicon
- ▶ Much easier assembly... Low module cost: factor 3 - 4 (no bump bonding)
- ▶ Can be thinner (100 μm or less, less radiation length) than planar sensors which have limited thinning due to the need for bump bonding
- ▶ Many suppliers now offering "High-voltage/high-resistivity" substrates, just what we need for full depletion
 - ▶ AMS 180 nm, LFoundry 150 nm, TowerJazz 180 nm, and many more
- ▶ Can we overcome the draw backs of the ALICE-MAPS approach?

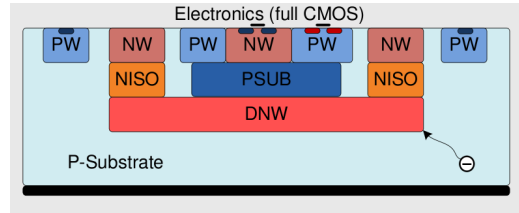
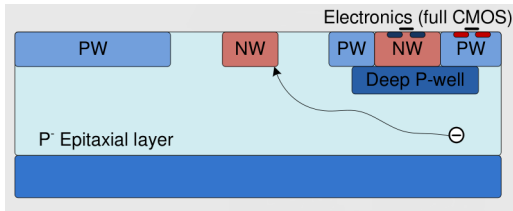
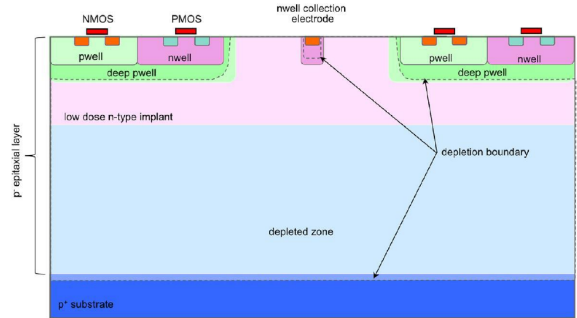


Figure: Left: MAPS in CMOS uses diffusion. Right: Depleted CMOS: deep n-well carries field below electronics, allowing full depletion and signal collection by drift. (T. Wang, Bonn.)

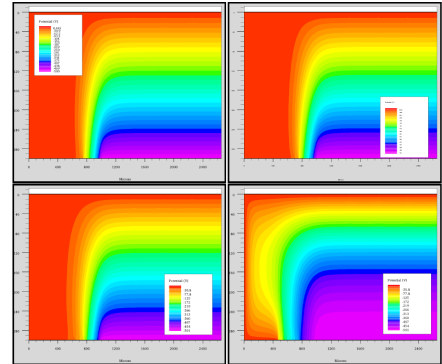
- ▶ Recent industry developments allow drift field to be applied across the signal region
 - ▶ Up to 40 V across 40 μm , large depletion region
 - ▶ Rad-hard with fast drift
 - ▶ Fully efficient over full area
 - ▶ BUT: high capacitance between “DNW” and “PSUB”, giving slow rise time and high noise

- ▶ TowerJazz offer a modified process, with deep n^- region carrying potential below electronics
- ▶ Small n^+ electrode maintains very low capacitance, hence fast and low noise
- ▶ Tested 2017: Fully efficient over whole pixel area; fast; rad-hard.



W. Snoeys, et al., NIM A 871 (2017) 90-96

- ▶ While simple formulae and approximations go a long way, calculations of E-field etc. for specific electrode designs gets very difficult
- ▶ Resort to finite element analysis programs
- ▶ Better still, use “Technology(-aware) Computer Aided Design”, TCAD from chip design industry
 - ▶ Several packages Cogenda, Sylvaco, Sentaurus, and some open-source versions
- ▶ Allows for very detailed design optimisation of guard ring structures, and particularly MAPS/CMOS sensors
- ▶ Higher prototype success rate, faster development, try out your crazy ideas



<https://cds.cern.ch/record/1233750> Lounis et al.

- ▶ Don't get the impression from textbooks that success of semiconductor detectors means we are at the end of the road:
 - ▶ We can imagine and achieve much more with technological advances
- ▶ It is a very active research field, in particle physics, industry, and many other fields
- ▶ 3D, SiPM, CMOS MAPS very active in development
- ▶ Race is on to get fully-depleted, digital-readout, monolithic CMOS into outer regions of ATLAS pixel detector